

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/791,186	LEE ET AL.
	<b>Examiner</b> Matthew G. Kayrish	<b>Art Unit</b> 2627

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPG-PUB, USPAT, USOCR, EPO, JPO, IBM_TDB, DERWENT, FPRS) (See Attached Search History)	10/5/2006	MK
EAST (USPG-PUB, USPAT, USOCR, EPO, JPO, IBM_TDB, DERWENT, FPRS) (See Attached Search History)	10/10/2006	MK
EAST (USPG-PUB, USPAT, USOCR, EPO, JPO, IBM_TDB, DERWENT, FPRS) (See Attached Search History)	10/11/2006	MK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner